ON Semiconductor

Is Now



To learn more about onsemi™, please visit our website at www.onsemi.com

onsemi and ONSEMI. and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. onsemi reserves the right to make changes at any time to any products or information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by onsemi. "Typical" parameters which may be provided in onsemi data sheets and/ or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. onsemi does not convey any license under any of its intellectual property rights nor the rights of others. onsemi products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use onsemi products for any such unintended or unauthorized application,

MOSFET – Power, Single, N-Channel, DPAK/IPAK

30 V, 68 A

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Three Package Variations for Design Flexibility
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- CPU Power Delivery
- DC-DC Converters

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Pa	Parameter				Unit
Drain-to-Source V	oltage		V_{DSS}	30	V
Gate-to-Source Vo	ltage	V_{GS}	±20	V	
Continuous Drain Current R _{θJA}		$T_A = 25^{\circ}C$ $T_A = 100^{\circ}C$	Ι _D	17.8 12.6	Α
(Note 1)		* *			
Power Dissipation R _{θJA} (Note 1)		T _A = 25°C	P _D	2.6	W
Continuous Drain		T _A = 25°C	I _D	13.0	Α
Current R _{θJA} (Note 2)	Steady	T _A = 100°C	1	9.2	
Power Dissipation R _{θJA} (Note 2)	State	T _A = 25°C	P _D	1.39	W
Continuous Drain Current $R_{\theta JC}$ (Note 1)		$T_{C} = 25^{\circ}C$ $T_{C} = 100^{\circ}C$	I _D	68 48	A
Power Dissipation R _{θJC} (Note 1)		T _C = 25°C	P _D	38.5	W
Pulsed Drain Current	t _p =10μs	T _A = 25°C	I _{DM}	248	Α
Current Limited by	Package	T _A = 25°C	I _{DmaxPkg}	76	Α
Operating Junction Temperature	Operating Junction and Storage Temperature				°C
Source Current (Bo	dy Diode)	I _S	35	Α	
Drain to Source dV	/dt	dV/dt	6.0	V/ns	
Energy (T _J = 25°C,	Single Pulse Drain-to-Source Avalanche Energy (T_J = 25°C, V_{DD} = 24 V, V_{GS} = 10 V, I_L = 31 A_{pk} , L = 0.1 mH, R_G = 25 Ω)			47	mJ
Lead Temperature (1/8" from case for		g Purposes	TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

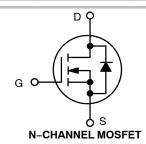
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.



ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	4.7 m Ω @ 10 V	68 A
	10 mΩ @ 4.5 V	00 A







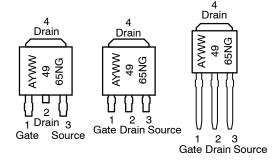


CASE 369AA DPAK (Bent Lead) STYLE 2

CASE 369AC 3 IPAK (Straight Lead)

CASE 369D IPAK (Straight Lead DPAK)

MARKING DIAGRAMS & PIN ASSIGNMENTS



A = Assembly Location

Y = Year WW = Work Week 4965N = Device Code G = Pb-Free Package

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 3 of this data sheet.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3.9	°C/W
Junction-to-TAB (Drain)	$R_{\theta JC-TAB}$	4.3	
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	57.6	
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	107.6	

- 3. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 4. Surface-mounted on FR4 board using the minimum recommended pad size.

Parameter	Symbol	Test Cond	dition	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				21.5		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25°C			1.0	
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{G}$	_S = ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D}$	= 250 μA	1.5	1.8	2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				4.1		mV/°
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		3.4	4.7	
			I _D = 15 A		3.4		1
		V _{GS} = 4.5 V	I _D = 30 A		5.4	10	mΩ
			I _D = 15 A		5.3		
Forward Transconductance	9 _{FS}	V _{DS} = 1.5 V, I _D = 30 A			52		S
CHARGES, CAPACITANCES AND GATE	RESISTANCE						
Input Capacitance	C _{ISS}				1710		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1.0 M	IHz, V _{DS} = 15 V		664		pF
Reverse Transfer Capacitance	C _{RSS}				340		
Total Gate Charge	Q _{G(TOT)}				17.2		
Threshold Gate Charge	Q _{G(TH)}		45.771 00.4		2.7		1
Gate-to-Source Charge	Q_GS	$V_{GS} = 4.5 \text{ V}, V_{DS} =$	15 V, I _D = 30 A		5.1		nC
Gate-to-Drain Charge	Q_{GD}				8.5		
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V}, I_D = 30 \text{ A}$			28.2		nC
SWITCHING CHARACTERISTICS (Note	6)			-		-	-
Turn-On Delay Time	t _{d(ON)}				12.1		
Rise Time	t _r	V _{GS} = 4.5 V, V	ns = 15 V.		34.2		7
Turn-Off Delay Time	t _{d(OFF)}	$I_D = 15 \text{ A}, R_G = 3.0 \Omega$			18.9		ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.

- 6. Switching characteristics are independent of operating junction temperatures.

7. Assume terminal length of 110 mils.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condi	tion	Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (No	ote 6)						
Turn-On Delay Time	t _{d(ON)}				8.3		
Rise Time	t _r	V _{GS} = 10 V, V _{DS}	s = 15 V,		21.5		ns
Turn-Off Delay Time	t _{d(OFF)}	$V_{GS} = 10 \text{ V, } V_{DS}$ $I_D = 15 \text{ A, } R_G = 10 \text{ N}$	= 3.0 Ω		24.4		
Fall Time	t _f				7.8		
DRAIN-SOURCE DIODE CHARACTE	RISTICS						
Forward Diode Voltage	V _{SD}	$V_{CS} = 0 \text{ V}$ $T_J = 25^{\circ}\text{C}$			0.86	1.1	
		$V_{GS} = 0 \text{ V},$ $I_{S} = 30 \text{ A}$ $I_{J} = 125^{\circ}$	T _J = 125°C		0.74		V
Reverse Recovery Time	t _{RR}	•			28.3		
Charge Time	t _a	V _{GS} = 0 V, dIS/dt =	= 100 A/μs,		13.3		ns
Discharge Time	t _b	I _S = 30 A			15]
Reverse Recovery Charge	Q _{RR}				16		nC
PACKAGE PARASITIC VALUES				-			
Source Inductance (Note 7)	L _S	T _A = 25°C			2.85		nH
Drain Inductance, DPAK	L _D				0.0164		
Drain Inductance, IPAK (Note 7)	L _D				1.88		
Gate Inductance (Note 7)	L _G				4.9		
Gate Resistance	R_{G}	1			1.0	2.2	Ω

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.

- 6. Switching characteristics are independent of operating junction temperatures.
 7. Assume terminal length of 110 mils.

ORDERING INFORMATION

Device	Package	Shipping [†]
NTD4965NT4G	DPAK (Pb-Free)	2500 / Tape & Reel
NTD4965N-1G	IPAK (Pb-Free)	75 Units / Rail
NTD4965N-35G	IPAK Trimmed Lead (Pb-Free)	75 Units / Rail

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

TYPICAL PERFORMANCE CURVES

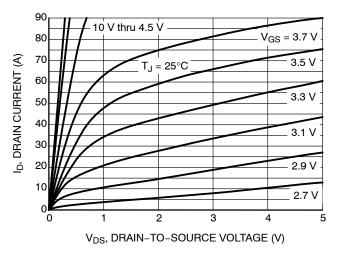
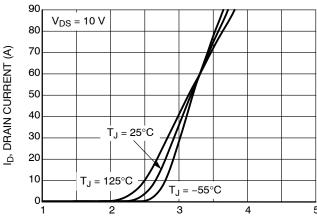


Figure 1. On-Region Characteristics



V_{GS}, GATE-TO-SOURCE VOLTAGE (V)

Figure 2. Transfer Characteristics

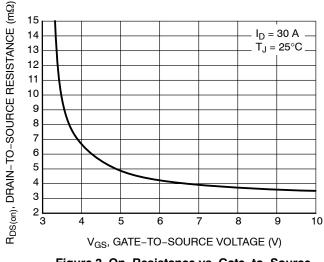


Figure 3. On-Resistance vs. Gate-to-Source Voltage

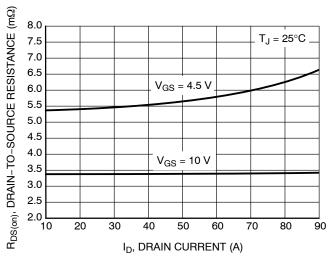


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

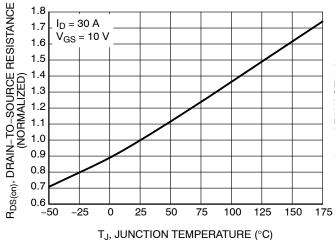
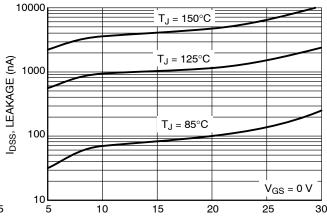


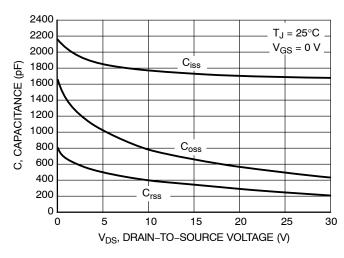
Figure 5. On–Resistance Variation with Temperature



V_{DS}, DRAIN-TO-SOURCE VOLTAGE (V)

Figure 6. Drain-to-Source Leakage Current vs. Voltage

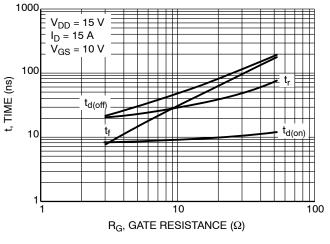
TYPICAL PERFORMANCE CURVES



10 V_{GS}, GATE-TO-SOURCE VOLTAGE (V) 9 8 7 6 5 Qgs Q_{gd} 4 3 $I_{D} = 30 \text{ A}$ $T_{.I} = 25^{\circ}C$ 2 $V_{DD} = 15 V$ $V_{GS} = 10 A$ 0 0 2 10 12 14 16 18 20 22 24 26 28 Q_G, TOTAL GATE CHARGE (nC)

Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge



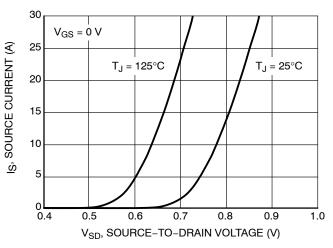
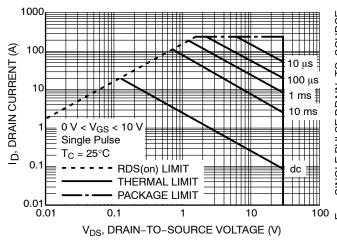


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current



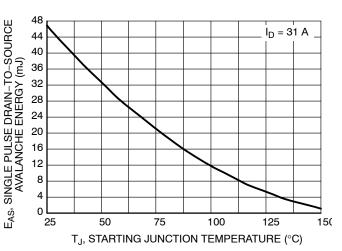


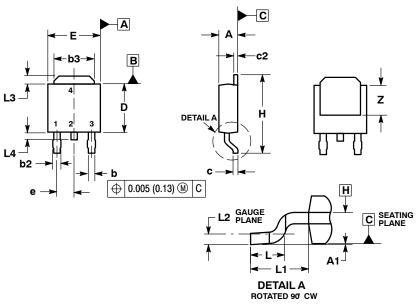
Figure 11. Maximum Rated Forward Biased Safe Operating Area

Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

PACKAGE DIMENSIONS

DPAK (SINGLE GUAGE)

CASE 369AA **ISSUE B**



NOTES:

- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

 2. CONTROLLING DIMENSION: INCHES.

 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS b3, L3 and Z.

 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.

 5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

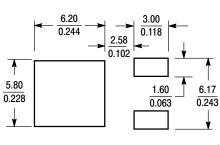
 6. DATUMS A AND B ARE DETERMINED AT DATUM
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INCHES		MILLIM	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
E	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29	BSC	
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108	REF	2.74 REF		
L2	0.020	BSC	0.51 BSC		
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE

4. DRAIN

SOLDERING FOOTPRINT*



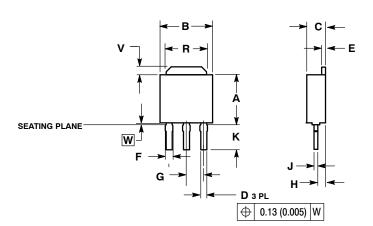
 $\left(\frac{\text{mm}}{\text{inches}}\right)$ SCALE 3:1

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

3 IPAK, STRAIGHT LEAD

CASE 369AC **ISSUE O**



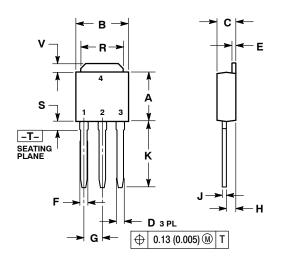
NOTES:

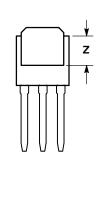
- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

- CONTROLLING DIMENSION: INCH.
 SEATING PLANE IS ON TOP OF DAMBAR POSITION.
 DIMENSION A DOES NOT INCLUDE DAMBAR POSITION OR MOLD GATE.

	INC	HES	MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.22
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.018	0.023	0.46	0.58
F	0.037	0.043	0.94	1.09
G	0.090	BSC	2.29	BSC
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.134	0.142	3.40	3.60
R	0.180	0.215	4.57	5.46
٧	0.035	0.050	0.89	1.27
w	0.000	0.010	0.000	0.25

IPAK CASE 369D **ISSUE C**





NOTES

- DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIM	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090	BSC	2.29	BSC
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
٧	0.035	0.050	0.89	1.27
Z	0.155		3.93	

STYLE 2: PIN 1. GATE

- DRAIN
 SOURCE
- DRAIN

ON Semiconductor and (III) are registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of SCILLC's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without particular purpose, for does Scribe as scribe any attaining arising out of the application of use of any product of circuit, and specifications can all an inability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all Claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA

Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada

Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910 Japan Customer Focus Center

Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative